PRESS RELEASE June 30th 2016

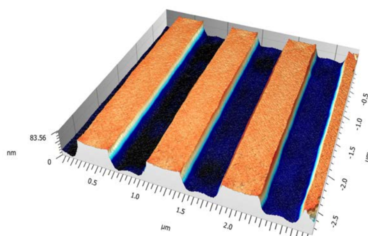
Advantest and Digital Surf Introduce PM3D Map

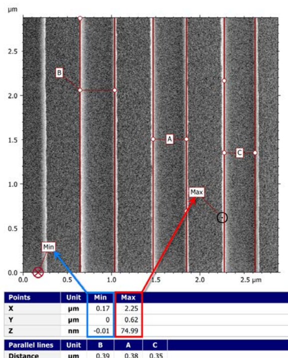
New surface imaging & metrology software based on Mountains® Technology

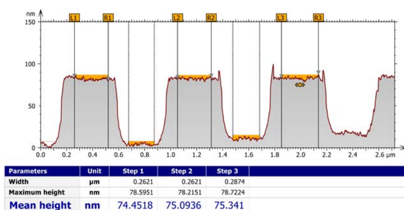
Tokyo, Japan & Besançon, France: Leading semiconductor test equipment supplier Advantest and Digital Surf announced that PM3D Map software based on Digital Surf's industry-standard Mountains Technology® is now incorporated into the company's leading-edge Multi Vision Metrology Scanning Electron Microscope (MVM-SEM®)* series. Advantest's MVM-SEM® system together with PM3D Map software now provide a complete solution for measuring the dimensions of nanoscale patterns on wafers, photomasks and other substrates.

"PM3D Map software is the tool of choice for SEM data analysis and metrology," stated Advantest. "It will greatly enhance our customers' experience by offering real-time 3D measurement tools, thus making a significant contribution to improving productivity."

"We're excited to bring the world-class Mountains® experience to users of Advantest's SEM metrology systems," said Christophe Mignot, Digital Surf CEO.







***Available in 11 different languages, PM3D Map software** enables visualization of 3D topography in real-time, analysis and generation of complete metrological reports. The new software provides a generous set of features for:*

- ***Surface geometry analysis** including measurement of the volume of surface structures (bumps, holes), step heights, contours etc.*
- ***Separation of surface roughness and waviness** using advanced ISO 16610 filtering techniques.*
- ***Characterization of surface texture** using the latest 3D parameters defined in the ISO 25178 standard.*

PM3D Map also offers powerful automation tools to speed up production. The interactive workflow allows full traceability and easy fine-tuning at any point in the measurement process.

Data can also be analyzed quickly by applying **templates** or macros.

Metrology reports can be exported in standard formats for publication (Excel, PDF and Word-compatible RTF). All images can be output at up to 1200dpi for integration into posters and presentations.

SEM metrology using PM3D Map.
From top to bottom: sample visualization in 3D, distance measurement & step height measurement from an extracted profile.

Data must meet certain requirements. Please contact us for more details.

*Multi Vision Metrology Scanning Electron Microscope MVM-SEM is the Advantest Corporation's registered trademark

Since 1954, Advantest has provided leading-edge support to the high-tech industry with measurement instruments that enable inspired engineering and promote technological progress.

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Digital Surf is the editor of Mountains® surface metrology and image analysis software for profilers and microscopes, integrated by leading instrument manufacturers worldwide.

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